1.   A method of detecting a portion of a half-toned uniform area in a half-toned bit-map comprising:

partitioning a half-toned bit map into a plurality of N-pixel tiles, each N-pixel tile having a marked pixel count M, and wherein the half-toned bit map is produced pursuant to a predetermined half-toning procedure;

comparing each N-pixel tile to a corresponding N-pixel reference tile that comprises a half-toned binary pattern that would be produced by the predetermined half-toning procedure for such N-pixel tile if the portion of a pre-half-toned data that resulted in such N-pixel tile were of uniform lightness;

identifying an N-pixel tile as comprising a portion of a half-toned uniform region if it matches the corresponding N-pixel reference tile.

2.   The method of claim 1 wherein comparing each N-pixel tile to an N-pixel reference tile comprises comparing each N-pixel tile to an associated N-pixel reference tile that comprises a half-toned binary pattern that would be produced by the predetermined half-toning procedure for such N-pixel tile if the portion of the original data that resulted in such N-pixel tile were of uniform lightness, wherein the N-pixel reference tile includes the same number of marked pixels M as the N-pixel tile to which it is being compared.

3.   A method of detecting a uniform area in a half-toned bit map comprising:

partitioning a half-toned bit map into a plurality of N-pixel tiles, each N-pixel tile having a marked pixel count M, wherein the half-toned bit map is produced pursuant to a predetermined threshold value array;

comparing each N-pixel tile to an associated N-pixel reference tile that comprises a half-toned binary pattern that would be produced for such N-pixel tile pursuant to the predetermined threshold value array if the portion of the original data that resulted in such N-pixel tile were of uniform lightness;

identifying an N-pixel tile as comprising a portion of a half-toned uniform region if it matches the corresponding N-pixel reference tile.

4.   The method of claim 11 wherein comparing each N-pixel tile to an N-pixel reference tile comprises comparing each N-pixel tile to an associated N-pixel reference tile that comprises a half-toned binary pattern that would be produced for such N-pixel tile pursuant to the predetermined threshold value array if the portion of the original data that resulted in such N-pixel tile were of uniform lightness, wherein the N-pixel reference tile includes the same number of marked pixels M as the N-pixel tile to which it is being compared.

5.   The method of claim 11 wherein comparing each N-pixel tile to an N-pixel reference tile comprises comparing each N-pixel tile to an associated N-pixel reference tile that comprises a half-toned binary pattern that would be produced for such N-pixel tile pursuant to the predetermined threshold value array if the portion of the original data that resulted in such N-pixel tile were of uniform lightness, wherein the pixels of the N-pixel reference tile are filled pursuant to a fill order that is based on the half-tone threshold values that produced such N-pixel tile.

6.   The method of claim 11 wherein comparing each N-pixel tile to an N-pixel reference tile comprises comparing each N-pixel tile to an associated N-pixel reference tile that comprises a half-toned binary pattern that would be produced for such N-pixel tile pursuant to the predetermined threshold value array if the portion of the original data that resulted in such N-pixel tile were of uniform lightness, wherein the pixels of the N-pixel reference tile are filled by normalizing the half-tone threshold values that produced such N-pixel tile.

7.   The method of claim 11 wherein comparing each N-pixel tile to an N-pixel reference tile comprises comparing each N-pixel tile to an associated N-pixel reference tile that comprises a half-toned binary pattern that would be produced for such N-pixel tile pursuant to the predetermined threshold value array if the portion of the original data that resulted in such N-pixel tile were of uniform lightness, wherein the pixels of the N-pixel reference tile are filled pursuant to a fill order pattern of fill order values that comprise a sequence that corresponds to a relative ordering of the half-tone threshold values that produced such N-pixel tile, wherein the fill order values are between 1 and N.

8.   A method of detecting a portion of a half-toned uniform area in a half-toned bit map comprising:

partitioning a half-toned bit map into a plurality of N-pixel tiles, each N-pixel tile having a marked pixel count M, wherein the half-toned bit map is produced pursuant to a predetermined threshold value array;

comparing each N-pixel tile to a corresponding N-pixel reference tile that comprises a half-toned binary pattern that comprises a portion of a half-toned uniform region and is based on the half-tone threshold values that produced the N-pixel tile;

identifying an N-pixel tile as comprising a portion of a half-toned uniform region if it matches the corresponding N-pixel reference tile.